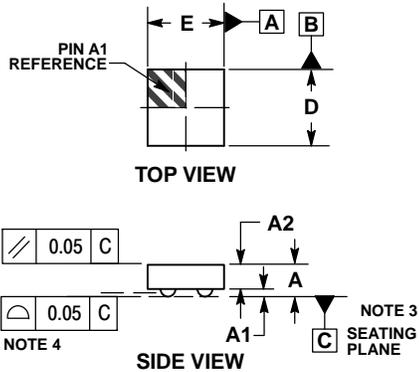




SCALE 4:1

WLCSP4, 0.84x0.84  
CASE 567KV  
ISSUE B

DATE 30 MAY 2017



NOTES:

1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
2. CONTROLLING DIMENSION: MILLIMETERS.
3. DATUM C, THE SEATING PLANE, IS DEFINED BY THE SPHERICAL CROWNS OF THE CONTACT BALLS.
4. COPLANARITY APPLIES TO SPHERICAL CROWNS OF THE SOLDER BALLS.
5. DIMENSION b IS MEASURED AT THE MAXIMUM CONTACT BALL DIAMETER PARALLEL TO DATUM C.

MILLIMETERS			
DIM	MIN	NOM	MAX
A	---	---	0.35
A1	0.08	0.10	0.12
A2	0.23 REF		
b	0.16	0.18	0.20
D	0.81	0.84	0.87
E	0.81	0.84	0.87
e	0.40 BSC		
e1	0.50 BSC		

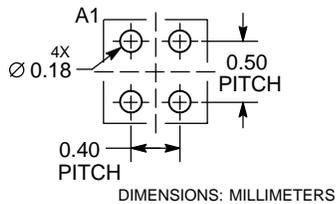
**GENERIC MARKING DIAGRAM\***



- X = Specific Device Code
- Y = Year
- W = Work Week

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "C" or microdot "•", may or may not be present. Some products may not follow the Generic Marking.

**RECOMMENDED SOLDERING FOOTPRINT\***



\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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<b>NEW STANDARD:</b>		
<b>DESCRIPTION:</b>	<b>WLCSP4, 0.84X0.84</b>	<b>PAGE 1 OF 2</b>

